



Product Change Notification / JAON-18KOPA638

Date:

14-Apr-2023

Product Category:

Broadband Gateway

PCN Type:

Manufacturing Change

Notification Subject:

CCB 5014.005 and 6258 Final Notice: Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9653AQC, LE9653AQCT, LE9621AQC, LE9643AQC, LE9621AQCT, and LE9643AQCT catalog part numbers (CPN) available in 36L VQFN (4x6x1mm) package assembled at MTAI assembly site.

Affected CPNs:

[JAON-18KOPA638_Affected_CPN_04142023.pdf](#)

[JAON-18KOPA638_Affected_CPN_04142023.csv](#)

Notification Text:

PCN Status:Final Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9653AQC, LE9653AQCT, LE9621AQC, LE9643AQC, LE9621AQCT, and LE9643AQCT catalog part numbers (CPN) available in 36L VQFN (4x6x1mm) package assembled at MTAI assembly site.

Pre and Post Change Summary:

		Pre Change		Post Change	
Fabrication Location	Die # 1	Global Foundries, Singapore - Fab 7 (GF07)		Global Foundries, Singapore - Fab 7 (GF07)	
	Die # 2	Global Foundries, Singapore - Fab 2 (GF02)	Microchip Technology Colorado – Fab 5 (MCSO)	Global Foundries, Singapore - Fab 2 (GF02)	Microchip Technology Colorado – Fab 5 (MCSO)
Die Size	Die # 1	2.204 x 2.258 mm		1.932x1.860mm	
		Please see attached pre and post change comparison for Die # 1 Location			
	Die # 2	1.57 x 1.72 mm		1.57 x 1.72 mm	
Assembly Site		Microchip Technology Thailand (HQ) (MTAI)		Microchip Technology Thailand (HQ) (MTAI)	
Wire Material		CuPdAu		CuPdAu	
Die Attach Material		3280		3280	
Molding Compound Material		G700LTD		G700LTD	
Lead Frame Material		A194		A194	

Impacts to Data Sheet:None

Change Impact:None

Reason for Change:To improve productivity by qualifying a new die size.

Change Implementation Status:In Progress

Estimated First Ship Date:May 6, 2023 (date code: 2318)

Note: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Time Table Summary:

	May 2022					>	April 2023				May 2023				
Workweek	1	2	2	2	2		1	1	1	1	1	19	20	21	22
	9	0	1	2	3		4	5	6	7	8				

Initial PCN Issue Date				X										
Qual Report Availability								X						
Final PCN Issue Date								X						
Estimated Implementation Date										X				

Method to Identify Change:Traceability code

Qualification Report:Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:May 24, 2022: Issued initial notification.

April 14, 2023: Issued final notification. Attached the qualification report and included the estimated first ship date on May 6, 2023.

The change described in this PCN does not alter Microchip’s current regulatory compliance regarding the material content of the applicable products.

Attachments:

- [PCN_JAON-18KOPA638 Pre_and_Post_Change_Summary.pdf](#)
- [PCN_JAON-18KOPA638_Qual_Report.pdf](#)

Please contact your local **Microchip sales office** with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to receive Microchip PCNs via email please register for our PCN email service at our **PCN home page** select register then fill in the required fields. You will find instructions about registering for

Microchips PCN email service in the [PCN FAQ](#) section.

If you wish to change your PCN profile, including opt out, please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.



MICROCHIP

QUALIFICATION REPORT SUMMARY
RELIABILITY LABORATORY

PCN# JAON-18KOPA638

Date:
March 31, 2023

Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9653AQC, LE9653AQCT, LE9621AQC, LE9643AQC, LE9621AQCT, and LE9643AQCT catalog part numbers (CPN) available in 36L VQFN (4x6x1mm) package assembled at MTAI assembly site.



MICROCHIP PACKAGE QUALIFICATION REPORT

Purpose	Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9653AQC, LE9653AQCT, LE9621AQC, LE9643AQC, LE9621AQCT, and LE9643AQCT catalog part numbers (CPN) available in 36L VQFN (4x6x1mm) package assembled at MTAI assembly site.
CN	E000125295
QUAL ID	R2201158 Rev A
MP CODE	3413G7M2CA01
Part No.	LE9643AQC
Bonding No.	BD-000491 Rev.02
CCB#	5014.005 and 6258
<u>Package</u>	
Type	36LD VQFN
Package size	4 x 6 x 1 mm
<u>Lead Frame</u>	
Paddle size	118 x 197 mils
Material	A194
Surface	Selective Ag Plating
Process	Etched
Lead Lock	Yes
Part Number	10103602
<u>Material</u>	
Epoxy	3280
Wire	CuPdAu wire
Mold Compound	G700LTD
Plating Composition	Matte Sn



MICROCHIP PACKAGE QUALIFICATION REPORT

Manufacturing Information

Assembly Lot No.	Wafer Lot#	Date Code
MTAI231702455.000	GF07923119810.110	2230867

Result

Pass Fail _____

36LD VQFN (4x6x1 mm) assembled by MTAI pass reliability test per QCI-39000.
This package was qualified the Moisture/Reflow Sensitivity Classification Level 3 at 260°C
reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
<u>Precondition</u> <u>Prior Perform</u> <u>Reliability Tests</u> (At MSL Level 3)	Electrical Test: +25°C System: Chroma3650	JESD22-A113	154(0)	0/154		Good Devices
	Bake 150°C, 24 hrs. System: CHINEE	JIP/ IPC/JEDEC		0/154		
	30°C/60%RH Moisture Soak 192 hrs. System: TABAI ESPEC Model PR-3SPH	J-STD-020E		0/154		
	3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243			0/154		
	Electrical Test: +25°C System: Chroma3650		154(0)	0/154	Pass	

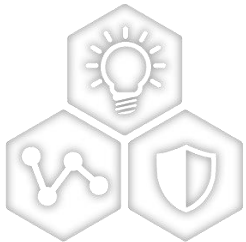
PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
UNBIASED- HAST	<p>Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X</p> <p>Electrical Test: +25°C System: Chroma3650</p> <p>Stress Condition: +130°C/85%RH, 192 hrs. System: HAST 6000X</p> <p>Electrical Test: +25°C System: Chroma3650</p>	JESD22- A118	77(0)	0/77 0/77 0/77	Pass Pass	<p>Parts had been pre-conditioned at 260°C</p> <p>77 units</p>
Wire sweep	Wire sweep Inspection 20 Wires	-	20(0) Wires	0/20	Pass	

CCB 5014.005 and 6258
Pre and Post Change Summary
PCN#: JAON-18KOPA638



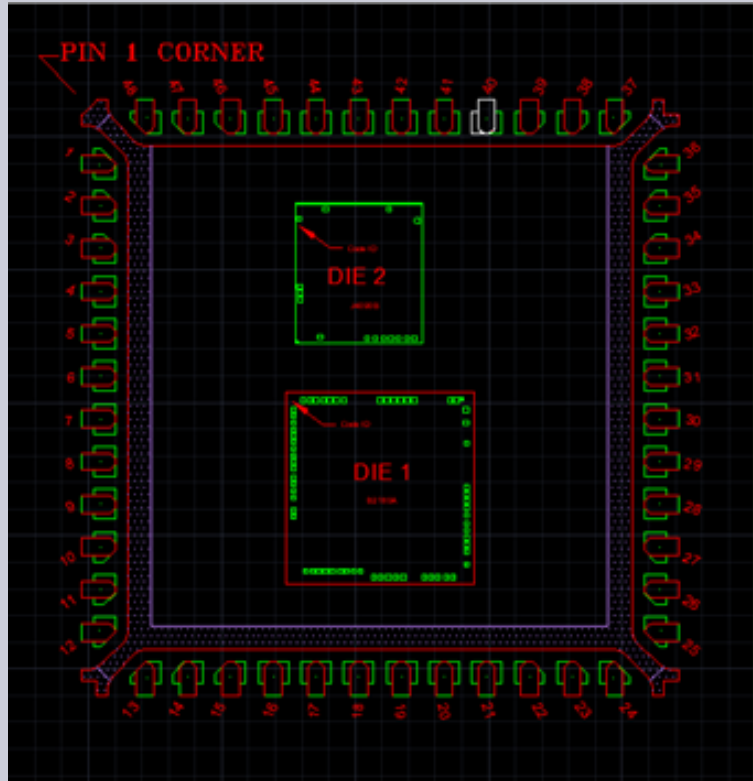
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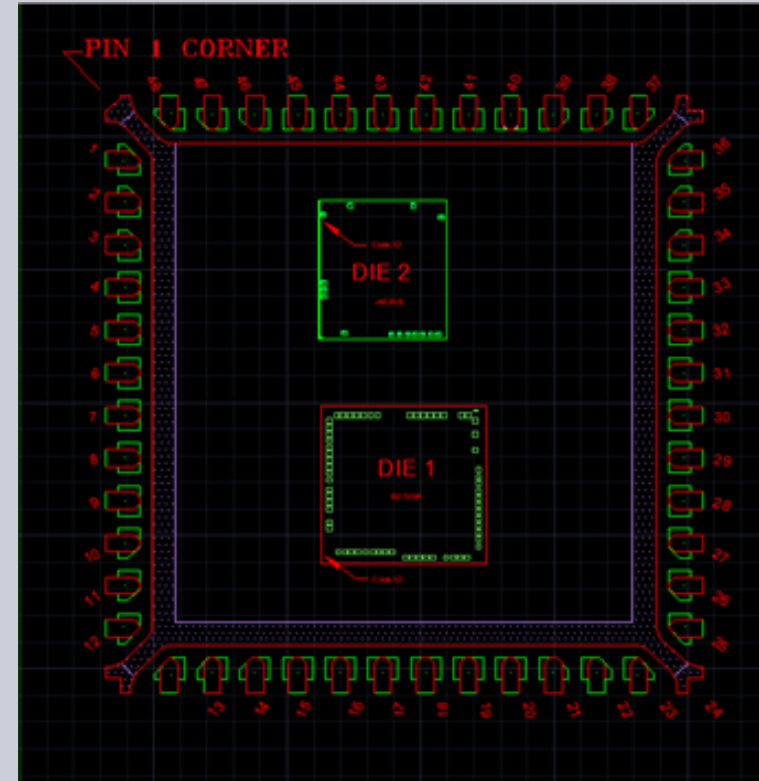
SMART | CONNECTED | SECURE

Pre and post change comparison

Pre change



Post Change



Note: Not-to-scale



MICROCHIP

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CN	E000125295
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MP CODE	3413G7M2CA01
Part No.	LE9643AQC
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	30°C/60%RH Moisture Soak 192 hrs. System: TABAI ESPEC Model PR-3SPH	J-STD-020E		0/154		
	3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243			0/154		
	Electrical Test: +25°C System: Chroma3650		154(0)	0/154	Pass	

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Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
UNBIASED- HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22- A118		0/77		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C System: Chroma3650		77(0)	0/77	Pass	77 units
	Stress Condition: +130°C/85%RH, 192 hrs. System: HAST 6000X			0/77		
	Electrical Test: +25°C System: Chroma3650		77(0)	0/77	Pass	
Wire sweep	Wire sweep Inspection 20 Wires	-	20(0) Wires	0/20	Pass	